

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/046,709	HATAKEYAMA, EIICHI	
Examiner		Art Unit		Page 1 of 1
MICHAEL R. ZECHER		3691		

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,999,907 A	12-1999	Donner, Irah H.	705/1
*	B	US-6,018,714 A	01-2000	Risen et al.	705/4
*	C	US-2001/0042034 A1	11-2001	Elliott, Douglas R.	705/35
*	D	US-6,330,547 B1	12-2001	Martin, David E.	705/38
*	E	US-2002/0046038 A1	04-2002	Prokoski, Francine J.	705/1
*	F	US-2002/0099637 A1	07-2002	Wilkinson et al.	705/36
*	G	US-2002/0087446 A1	07-2002	Reddy, Sada L.	705/36
*	H	US-2002/0165811 A1	11-2002	Ishii et al.	705/36
*	I	US-2003/0167175 A1	09-2003	Salom, Silvio	705/1
*	J	US-7,292,994 B2	11-2007	Prokoski, Francine J.	705/35
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.